

CMOS Quad 2-Input NAND Schmitt Triggers

High-Voltage Types (20 Volt Rating)

■ CD4093B consists of four Schmitt-trigger circuits. Each circuit functions as a two-input NAND gate with Schmitt-trigger action on both inputs. The gate switches at different points for positive- and negative-going signals. The difference between the positive voltage (V_P) and the negative voltage (V_N) is defined as hysteresis voltage (V_H) (see Fig. 2).

The CD4093 types are supplied in a 14-lead hermetic dual-in-line ceramic package (F suffix), 14-lead dual-in-line plastic package (E suffix), 14-lead dual-in-line plastic small-outline package (M), and in chip form (H suffix). Add the suffix 96 to the M package for tape and reel.

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (V_{DD})

Voltages referenced to V_{SS} Terminal) -0.5V to +20V

INPUT VOLTAGE RANGE, ALL INPUTS -0.5V to $V_{DD} + 0.5V$

DC INPUT CURRENT, ANY ONE INPUT $\pm 10\text{mA}$

PACKAGE THERMAL IMPEDANCE, θ_{JA} (See Note 1):

E package 80°C/W

M package 86°C/W

DEVICE DISSIPATION PER OUTPUT TRANSISTOR

FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) 100mW

OPERATING-TEMPERATURE RANGE (T_A) -55°C to $+125^\circ\text{C}$

STORAGE TEMPERATURE RANGE (T_{stg}) -65°C to $+150^\circ\text{C}$

LEAD TEMPERATURE (DURING SOLDERING):

At distance $1/16 \pm 1/32$ inch ($1.59 \pm 0.79\text{mm}$) from case for 10s max $+265^\circ\text{C}$

NOTE 1: Package thermal impedance is calculated in accordance with JESD 51.

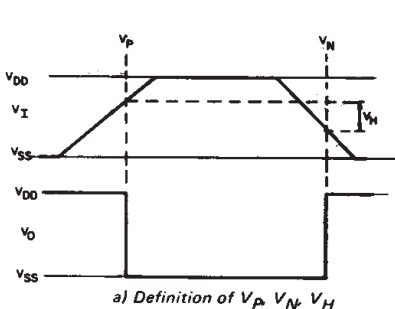
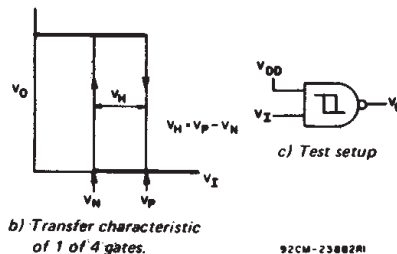
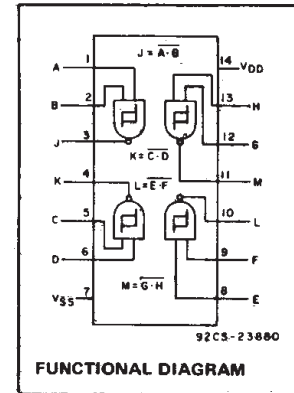


Fig. 2 – Hysteresis definition, characteristic, and test setup.



92CM-23882M



Features:

- Schmitt-trigger action on each input with no external components
- Hysteresis voltage typically 0.9 V at $V_{DD} = 5\text{ V}$ and 2.3 V at $V_{DD} = 10\text{ V}$
- Noise immunity greater than 50%
- No limit on input rise and fall times
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of $1\text{ }\mu\text{A}$ at 18 V over full package-temperature range, 100 nA at 18 V and 25°C
- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

- Wave and pulse shapers
- High-noise-environment systems
- Monostable multivibrators
- Astable multivibrators
- NAND logic

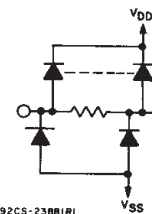
RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges.

CHARACTERISTIC	MIN.	MAX.	UNITS
Supply Voltage Range (T_A = Full Package Temp. Range)	3	18	V



* ALL INPUTS PROTECTED BY CMOS PROTECTION NETWORK



92CS-23881R1

Fig. 1 – Logic diagram—1 of 4 Schmitt triggers.

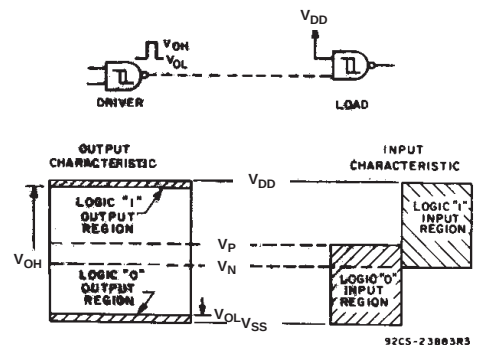


Fig. 3 – Input and output characteristics.

CD4093B Types

STATIC ELECTRICAL CHARACTERISTICS

CHARACTER- ISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
	V _O (V)	V _{IN} (V)	V _{DD} (V)	-55	-40	+85	+125	+25			
								MIN.	TYP.	MAX.	
Quiescent Device Current, I _{DD} Max.	—	0.5	5	1	1	30	30	—	0.02	1	μA
	—	0.10	10	2	2	60	60	—	0.02	2	
	—	0.15	15	4	4	120	120	—	0.02	4	
	—	0.20	20	20	20	600	600	—	0.04	20	
Positive Trigger Threshold Voltage V _p Min.	—	a	5	2.2	2.2	2.2	2.2	2.2	2.9	—	V
	—	a	10	4.6	4.6	4.6	4.6	4.6	5.9	—	
	—	a	15	6.8	6.8	6.8	6.8	6.8	8.8	—	
	—	b	5	2.6	2.6	2.6	2.6	2.6	3.3	—	
	—	b	10	5.6	5.6	5.6	5.6	5.6	7	—	
	—	b	15	6.3	6.3	6.3	6.3	6.3	9.4	—	
V _p Max.	—	a	5	3.6	3.6	3.6	3.6	—	2.9	3.6	V
	—	a	10	7.1	7.1	7.1	7.1	—	5.9	7.1	
	—	a	15	10.8	10.8	10.8	10.8	—	8.8	10.8	
	—	b	5	4	4	4	4	—	3.3	4	
	—	b	10	8.2	8.2	8.2	8.2	—	7	8.2	
	—	b	15	12.7	12.7	12.7	12.7	—	9.4	12.7	
Negative Trigger Threshold Voltage V _N Min.	—	a	5	0.9	0.9	0.9	0.9	0.9	1.9	—	V
	—	a	10	2.5	2.5	2.5	2.5	2.5	3.9	—	
	—	a	15	4	4	4	4	4	5.8	—	
	—	b	5	1.4	1.4	1.4	1.4	1.4	2.3	—	
	—	b	10	3.4	3.4	3.4	3.4	3.4	5.1	—	
	—	b	15	4.8	4.8	4.8	4.8	4.8	7.3	—	
V _N Max.	—	a	5	2.8	2.8	2.8	2.8	—	1.9	2.8	V
	—	a	10	5.2	5.2	5.2	5.2	—	3.9	5.2	
	—	a	15	7.4	7.4	7.4	7.4	—	5.8	7.4	
	—	b	5	3.2	3.2	3.2	3.2	—	2.3	3.2	
	—	b	10	6.6	6.6	6.6	6.6	—	5.1	6.6	
	—	b	15	9.6	9.6	9.6	9.6	—	7.3	9.6	
Hysteresis Voltage V _H Min.	—	a	5	0.3	0.3	0.3	0.3	0.3	0.9	—	V
	—	a	10	1.2	1.2	1.2	1.2	1.2	2.3	—	
	—	a	15	1.6	1.6	1.6	1.6	1.6	3.5	—	
	—	b	5	0.3	0.3	0.3	0.3	0.3	0.9	—	
	—	b	10	1.2	1.2	1.2	1.2	1.2	2.3	—	
	—	b	15	1.6	1.6	1.6	1.6	1.6	3.5	—	
V _H Max.	—	a	5	1.6	1.6	1.6	1.6	—	0.9	1.6	V
	—	a	10	3.4	3.4	3.4	3.4	—	2.3	3.4	
	—	a	15	5	5	5	5	—	3.5	5	
	—	b	5	1.6	1.6	1.6	1.6	—	0.9	1.6	
	—	b	10	3.4	3.4	3.4	3.4	—	2.3	3.4	
	—	b	15	5	5	5	5	—	3.5	5	

^a Input on terminals 1,5,8,12 or 2,6,9,13; other inputs to V_{DD}.

^b Input on terminals 1 and 2, 5 and 6, 8 and 9, or 12 and 13; other inputs to V_{DD}.

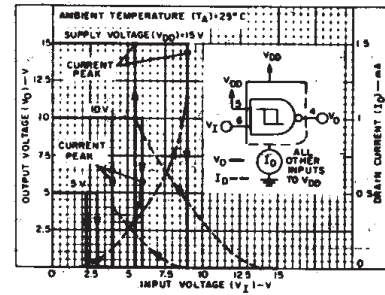


Fig. 4 — Typical current and voltage transfer characteristics.

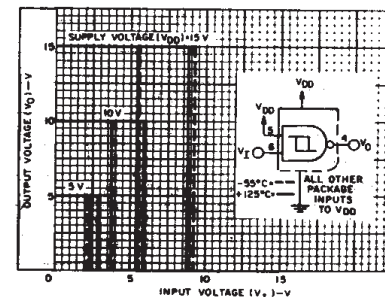


Fig. 5 — Typical voltage transfer characteristics as a function of temperature.

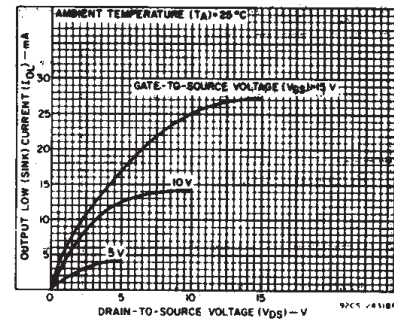


Fig. 6 — Typical output low (sink) current characteristics.

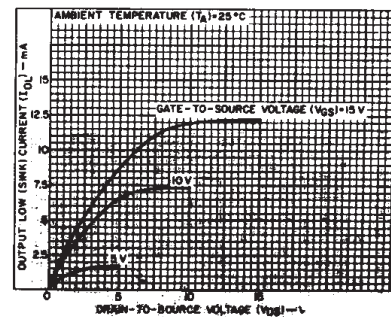


Fig. 7 — Minimum output low (sink) current characteristics.

CD4093B Types

STATIC ELECTRICAL CHARACTERISTICS (CONT'D)

CHARACTER- ISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
	V _O (V)	V _{IN} (V)	V _{DD} (V)	-55	-40	+85	+125	+25			
								MIN.	TYP.	MAX.	
Output Low (Sink) Current, I _{OL} Min.	0.4	0.5	5	0.64	0.61	0.42	0.36	0.51	1	—	mA
	0.5	0.10	10	1.6	1.5	1.1	0.9	1.3	2.6	—	
	1.5	0.15	15	4.2	4	2.8	2.4	3.4	6.8	—	
Output High (Source) Current, I _{OH} Min.	4.6	0.5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	—	mA
	2.5	0.5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	—	
	9.5	0.10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	—	
	13.5	0.15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	—	
Output Voltage Low-Level, V _{OL} Max.	—	0.5	5	0.05				—	0	0.05	V
	—	0.10	10	0.05				—	0	0.05	
	—	0.15	15	0.05				—	0	0.05	
Output Voltage High-Level, V _{OH} Min.	—	0.5	5	4.95				4.95	5	—	V
	—	0.10	10	9.95				9.95	10	—	
	—	0.15	15	14.95				14.95	—	—	
Input Current, I _{IN} Max.	—	0.18	18	±0.1	±0.1	±1	±1	—	±10 ⁻⁵	±0.1	μA

DYNAMIC ELECTRICAL CHARACTERISTICS

At $T_A = 25^\circ\text{C}$; Input $t_r, t_f = 20\text{ ns}$, $C_L = 50\text{ pF}$, $R_L = 200\text{ k}\Omega$

CHARACTERISTIC	TEST CONDITIONS	LIMITS		UNITS	
		V _{DD} VOLTS	TYP.		MAX.
Propagation Delay Time: t _{PHL} , t _{PLH}		5	190	380	ns
		10	90	180	
		15	65	130	
Transition Time, t _{THL} , t _{TLH}		5	100	200	ns
		10	50	100	
		15	40	80	
Input Capacitance, C _{IN}	Any Input		5	7.5	pF

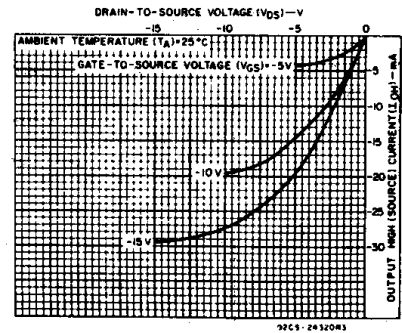


Fig. 8 - Typical output high (source) current characteristics.

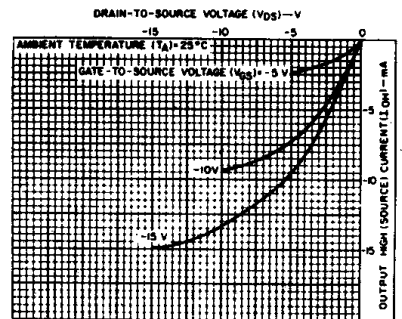


Fig. 9 - Minimum output high (source) current characteristics.

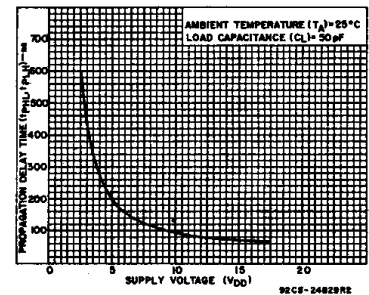


Fig. 10 - Typical propagation delay time vs. supply voltage.

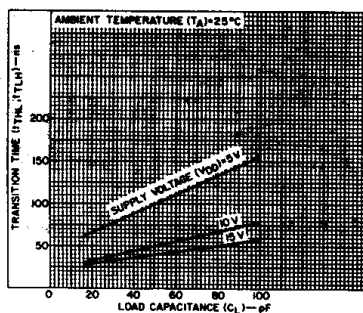


Fig. 11 - Typical transition time vs. load capacitance.

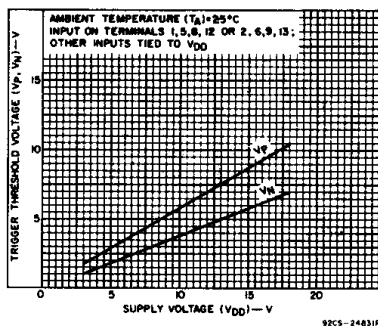


Fig. 12 - Typical trigger threshold voltage vs. V_{DD} .

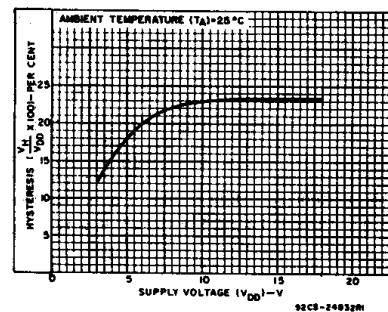


Fig. 13 - Typical per cent hysteresis vs. supply voltage.

CD4093B Types

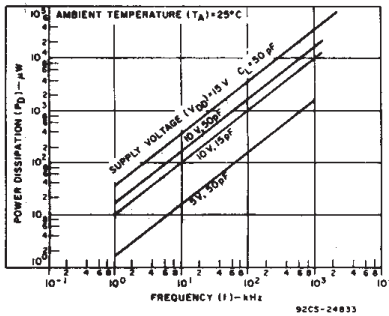


Fig. 14 - Typical power dissipation vs. frequency characteristics.

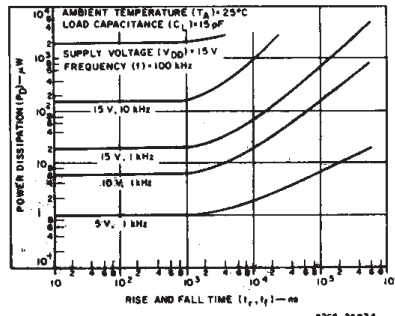


Fig. 15 - Typical power dissipation vs. rise and fall times.

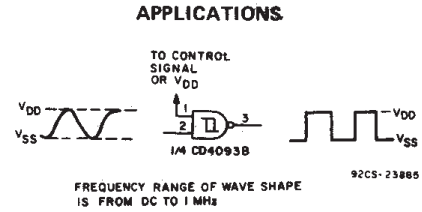


Fig. 16 - Wave shaper.

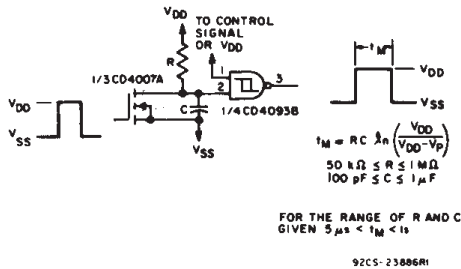


Fig. 17 - Monostable multivibrator.

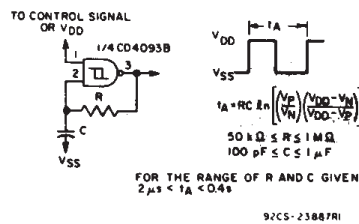


Fig. 18 - Astable multivibrator.

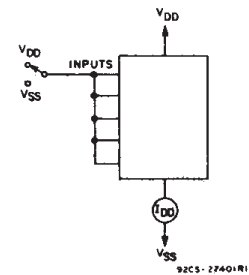


Fig. 19 - Quiescent device current test circuit.

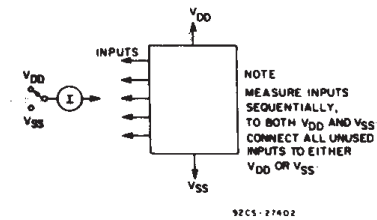


Fig. 20 - Input current test circuit.

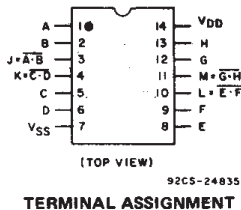


Fig. 21 - Contact Debouncer

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